

Form PTO-1449
REV. 7-82

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

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LIST OF PRIOR ART CITED BY APPLICANT
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John et al.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPR PRIATE
AA	5373359	12/1994	Woodman et al.	356	328	
AB	5666201	9/1997	John et al.	356	369	
AC	6268917	7/2001	John	356	369	
AD	5872630	2/1999	John et al.	356	369	
AE	5757494	5/1998	Gren et al.	356	369	
AF	5956145	9/1999	Gren et al.	356	364	
AG	5963327	10/1999	He et al.	356	369	
AH	4826321	5/1989	Coates et al.	356	351	
AI	5155623	10/1992	Miller et al.	359	495	
AJ	5581350	12/1996	Chen et al.	356	369	
AK	5329357	7/1994	Berneux et al.	356	369	

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL	1518728		<i>Soviet</i>				
AM							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AR	
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Form PTO-1449
REV. 7-80

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Joh, et al.

FILING DATE

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	4053232	10/1997	Pill et al.	356	118	
AB	4647207	3/1987	Bjork et al	356	369	
AC	5179462	1/1993	Kagayama et al.	359	204	
AD	4982206	1/1991	Heerle et al.	346	108	
AE	3947688	3/1976	Murray	250	455	
AF						
AG						
AH						
AI						
AJ						
AK						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
AL							
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PLEASE USE THE FOLLOWING FOR PTO FORM 1449 FOR ARTICLES

Paper by Johs, titled "Regression Calibration Method for Rotating Element Ellipsometers", Thin Solid Films, 234 (1993).

A paper by Smith, "An Automated Scanning Ellipsometer", Surface Science, Vol. 56, No. 1 (1976) is identified as it describes an ellipsometer which does not require moving (ie. rotating), elements during data collection.

Papers, by Azzam and Azzam et al. are also identified:

"Multichannel Polarization State Detectors For Time-Resolved Ellipsometry", Thin Solid Film, 234 (1993); and

"Spectrophotopolarimeter Based On Multiple Reflections In A Coated Dielectric Slab", Thin Solid Films 313 (1998); and

Review paper by Collins, titled "Automatic Rotating Element Ellipsometers: Calibration, Operation and Real-Time Applications", Rev. Sci. Instrum., 61(8) (1990), is identified for general information.